

Search Notes



Application/Control No.

10/825,806

Examiner

David T. Fidei

Applicant(s)/Patent under Reexamination

TAKAHASHI ET AL.

Art Unit

3728

SEARCHED

Class	Subclass	Date	Examiner
206	219 220 222		
215	Dig.8	10/2/2005	DTF

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

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